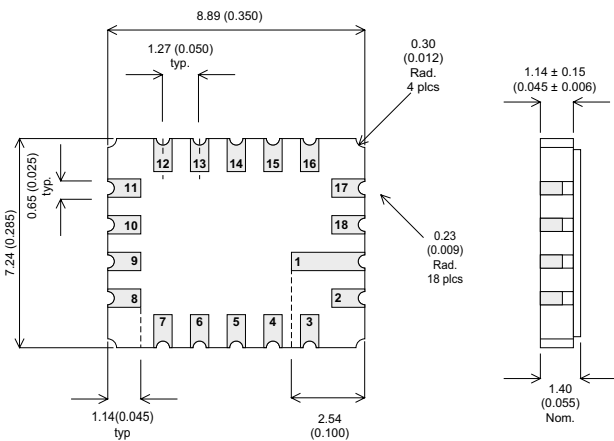


**MULTI-CHIP ARRAY
TWO NPN AND TWO PNP
HIGH SPEED, MEDIUM POWER
SWITCHING TRANSISTORS IN A
HERMETICALLY SEALED
CERAMIC SURFACE MOUNT PACKAGE**

MECHANICAL DATA

Dimensions in mm (inches)



Pinout:

NPN	PNP	PNP	NPN
2 = E1	6 = C2	11 = E3	15 = C4
3 = B1	7 = B2	12 = B3	16 = B4
4 = C1	8 = E2	13 = C3	17 = E4

1,5,9,10,14,18 NO CONNECTION

DESCRIPTION

The MCA104 is a ceramic surface mount transistor array designed for high reliability applications.

It contains 2 NPN Bipolar Transistors and 2 PNP Bipolar Transistors.

FEATURES

- Ceramic Surface Mount Package.
- Screening Options Available

NPN DEVICES

- $V_{CBO} = 75V$
- $V_{CBO} = 400V$
- $I_C = 600mA$

PNP DEVICES

- $V_{CBO} = 60V$
- $V_{CEO} = 60V$
- $I_C = 600mA$

ABSOLUTE MAXIMUM RATINGS

		NPN Channel	PNP Channel
V_{CBO}	Collector - Base Voltage	75V	-60V
V_{CEO}	Collector - Emitter Voltage	40V	- 60V
V_{EBO}	Emitter - Base Voltage	6	-5
I_C	Collector Current (per device)	600mA	600mA
P_D	Power Dissipation (per device)	350mW	350mW
θ_{j-a}	Thermal Resistance (junction to ambient)	350°C	
T_j, T_{stg}	Storage, Junction Temperature	-55 to +200°C	

ELECTRICAL CHARACTERISTICS ($T_{case} = 25^{\circ}C$ unless otherwise stated) **NPN DEVICES**

Parameter	Test Conditions	Min.	Typ.	Max.	Unit		
$V_{CEO(sus)}$ * Collector – Emitter Sustaining Voltage	$I_C = 10mA$	40			V		
$V_{(BR)CBO}$ * Collector – Base Breakdown Voltage	$I_C = 10\mu A$	75			V		
$V_{(BR)EBO}$ * Emitter – Base Breakdown Voltage	$I_E = 10\mu A$ $I_C = 0$	6			V		
I_{CEX} * Collector Cut-off Current ($I_C = 0$)	$I_B = 0$ $V_{CE} = 60V$			10	nA		
I_{CBO} * Collector – Base Cut-off Current	$I_E = 0$ $V_{CB} = 60V$			10	nA		
	$T_C = 125^{\circ}C$			10	μA		
I_{EBO} * Emitter Cut-off Current ($I_C = 0$)	$I_C = 0$ $V_{EB} = 3V$ (off)			10	nA		
I_{BL} * Base Current	$V_{CE} = 60V$ $V_{EB} = 3V$ (off)			20	nA		
$V_{CE(sat)}$ * Collector – Emitter Saturation Voltage	$I_C = 150mA$ $I_B = 15mA$			0.3	V		
	$I_C = 500mA$ $I_B = 50mA$			1			
$V_{BE(sat)}$ * Base – Emitter Saturation Voltage	$I_C = 150mA$ $I_B = 15mA$	0.6		1.2	V		
	$I_C = 500mA$ $I_C = 50mA$			2			
h_{FE} * DC Current Gain	$T_A = -55^{\circ}C$	$I_C = 0.1mA$ $V_{CE} = 10V$			35	—	
		$I_C = 1mA$ $V_{CE} = 10V$			50		
		$I_C = 10mA$ $V_{CE} = 10V$			75		
		$I_C = 10mA$ $V_{CE} = 10V$			35		
		$I_C = 150mA$ $V_{CE} = 10V$			100		300
		$I_C = 150mA$ $V_{CE} = 1V$			50		
		$I_C = 500mA$ $V_{CE} = 10V$			40		

* Pulse test $t_p = 300\mu s$, $\delta \leq 2\%$

DYNAMIC CHARACTERISTICS ($T_{case} = 25^{\circ}C$ unless otherwise stated) **NPN DEVICES**

Parameter	Test Conditions	Min.	Typ.	Max.	Unit
f_T Transition Frequency	$I_C = 20mA$ $V_{CE} = 20V$ $f = 100MHz$	300			MHz
C_{ob} Output Capacitance	$V_{CB} = 10V$ $I_E = 0$ $f = 1.0MHz$			8	pF
C_{ib} Input Capacitance	$V_{BE} = 0.5V$ $I_C = 0$ $f = 1.0MHz$			30	pF
h_{fe} Small Signal Current Gain	$I_C = 1mA$ $V_{CE} = 10V$ $f = 1kHz$	50		300	
	$I_C = 10mA$ $V_{CE} = 10V$ $f = 1kHz$	75		375	

SWITCHING CHARACTERISTICS (RESISTIVE LOAD) ($T_{case} = 25^{\circ}C$ unless otherwise stated)

Parameter	Test Conditions	Min.	Typ.	Max.	Unit
t_d Delay Time	$V_{CC} = 30V$ $V_{BE} = 0.5V$ (off)			10	ns
t_r Rise Time	$I_{C1} = 150mA$ $I_{B1} = 15mA$			25	ns
t_s Storage Time	$V_{CC} = 30V$ $I_C = 150mA$			225	ns
t_f Fall Time	$I_{B1} = I_{B2} = 15mA$			60	ns

f_T is defined as the frequency at which h_{FE} extrapolates to unity.

ELECTRICAL CHARACTERISTICS ($T_{case} = 25^{\circ}C$ unless otherwise stated) **PNP DEVICES**

Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{CEO(sus)}^*$ Collector – Emitter Sustaining Voltage	$I_C = 10mA$	-60			V
$V_{(BR)CBO}^*$ Collector – Base Breakdown Voltage	$I_C = 10\mu A$	-60			V
$V_{(BR)EBO}^*$ Emitter – Base Breakdown Voltage	$I_E = 10\mu A$ $I_C = 0$	-5			V
I_{CEX}^* Collector Cut-off Current	$V_{CE} = 30V$ $V_{BE} = 0.5V$			50	nA
I_{CBO}^* Collector – Base Cut-off Current	$I_E = 0$ $V_{CB} = 50V$			0.01	μA
	$T_C = 125^{\circ}C$			10	
I_{BEO} Base Cut-off Current	$V_{CE} = 30V$ $V_{BE} = 0.5V$			50	nA
$V_{CE(sat)}^*$ Collector – Emitter Saturation Voltage	$I_C = 150mA$ $I_B = 15mA$			-0.4	V
	$I_C = 500mA$ $I_B = 50mA$			-1.6	
$V_{BE(sat)}^*$ Base – Emitter Saturation Voltage	$I_C = 150mA$ $I_B = 15mA$			-1.3	V
	$I_C = 500mA$ $I_B = 50mA$			-2.6	
h_{FE}^* DC Current Gain	$I_C = 0.1mA$ $V_{CE} = 10V$	75			—
	$I_C = 1mA$ $V_{CE} = 10V$	100			
	$I_C = 10mA$ $V_{CE} = 10V$	100			
	$I_C = 150mA$ $V_{CE} = 10V$	100		300	
	$I_C = 500mA$ $V_{CE} = 10V$	50			

* Pulse test $t_p = 300\mu s$, $\delta \leq 2\%$

DYNAMIC CHARACTERISTICS ($T_{case} = 25^{\circ}C$ unless otherwise stated) **PNP DEVICES**

Parameter	Test Conditions	Min.	Typ.	Max.	Unit
f_T Transition Frequency	$I_C = 50mA$ $V_{CE} = 20V$ $f = 100MHz$	200			MHz
C_{ob} Output Capacitance	$V_{CB} = 10V$ $I_E = 0$ $f = 1.0MHz$			8	pF
C_{ib} Input Capacitance	$V_{BE} = 2V$ $I_C = 0$ $f = 1.0MHz$			30	pF

ELECTRICAL CHARACTERISTICS ($T_{case} = 25^{\circ}C$ unless otherwise stated)

Parameter	Test Conditions	Min.	Typ.	Max.	Unit
t_{on} Turn-on Time	$V_{CC} = 30V$		26	45	ns
t_d Delay Time	$I_C = 150mA$		6.0	10	
t_r Rise Time	$I_{B1} = 15mA$		20	40	
t_{off} Turn-off Time	$V_{CC} = 6V$		70	100	ns
t_s Storage Time	$I_C = 150mA$		50	80	
t_f Fall Time	$I_{B1} = I_{B2} = 15mA$		20	30	